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500.37149X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**  
**EXPEDITED PROCEDURE PURSUANT**  
**TO 37 CFR §1.116 REQUESTED**  
**Attn: Mail Stop AF**

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**RECEIVED**

**APR 05 2004**

**Technology Center 2600**

Applicants: Shunji MAEDA et al.

Serial No.: 09/294,137

Filed: April 20, 1999

For: **DEFECT INSPECTION METHOD AND APPARATUS**

Group: 2621

Examiner: Brian P. Werner

**AMENDMENT AFTER FINAL**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450  
**Attn: Mail Stop AF**

**March 31, 2004**

Sir:

In response to the final Office Action (Paper No. 25) dated on December 4, 2003, please amend the above-identified application as follows.

**Amendments to the Claims** begin on page 3 of this paper.

**Remarks/Arguments** begin on page 13 of this paper.